

Title of Change:	Part numbering and site change related to the integration of SWIR Vision Systems acquired by onsemi.							
Effective date:	04 Nov 2024							
Contact information:	Contact your local onsemi Sales Office.							
Type of notification:	This Product Bulletin is for notification purposes only. onsemi will proceed with implementation of this change upon publication of this Product Bulletin.							
Change Category:	Test Change, Assembly Change, Wafer Fab Change							
Change Sub-Category(s):	Change in Part Numbering, Manufacturing Site Transfer							
Sites Affected:								
onsemi Sites	External Foundry/Subcon Sites							
onsemi, Durham, United States	None							
Description and Purpose:								
SWIR Vision Systems was acquired by onsemi on July 2nd, 2024 (announcement). As part of the integration of SWIR Vision Systems into onsemi, it is necessary to change the SWIR orderable part numbers to meet onsemi's system's Orderable Part Number (OPN) nomenclature. The orderable part numbers that will change are in the Affected Part List attached to this notice. Specifically, the SWIR Part Numbers will no longer be utilized, effective November 4th, 2024. New orders will need to use the new onsemi OPN, and all existing orders will be converted with the new onsemi OPN. onsemi will be modifying all datasheets associated with the former SWIR Vision Systems products to incorporate the OPN changes. Additionally, some of the manufacturing processes will be transferred to a different site as indicated in the table below. This transfer will be effective in December 2024. No change to the Form, Fit, or Function is expected. <table border="1" data-bbox="94 1146 1516 1247"> <thead> <tr> <th></th><th>From</th><th>To</th></tr> </thead> <tbody> <tr> <td>CQD Photodiode wafer preparation, assembly of the sensor, testing and calibration</td><td>Micross, US</td><td>onsemi, Durham, United States</td></tr> </tbody> </table>				From	To	CQD Photodiode wafer preparation, assembly of the sensor, testing and calibration	Micross, US	onsemi, Durham, United States
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CQD Photodiode wafer preparation, assembly of the sensor, testing and calibration	Micross, US	onsemi, Durham, United States						
List of Affected Parts:								
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